

TOSHIBA Bipolar Linear Integrated Circuit Silicon Monolithic

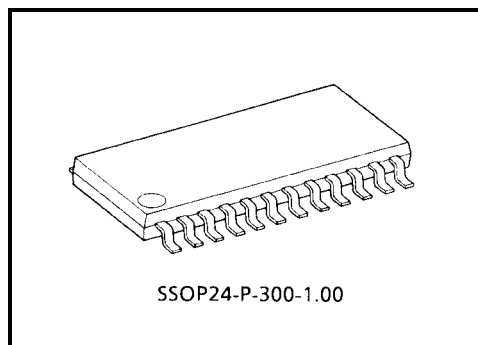
TA2109F

RF Amplifier for Digital Servo CD System

TA2109F is a 3-beam type PUH compatible RF Amplifier for Digital Servo to be used in the CD system.
In combination with a CMOS single chip processor TC9432AF/TC9462F a CD system can be composed very simply.

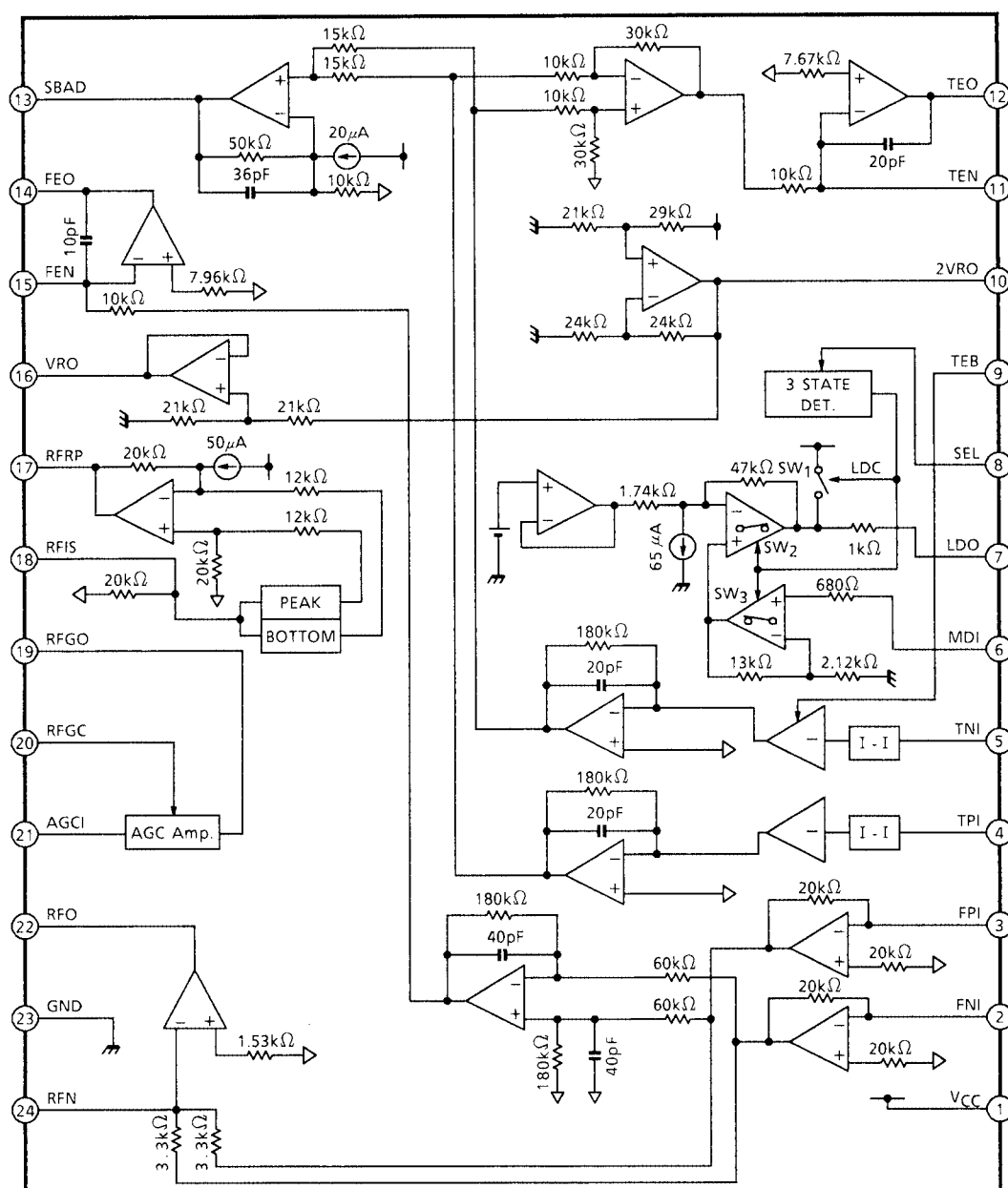
Features

- Built in amplifier for reference (V_{REF} , $2 V_{REF}$) supply.
- Built in Auto Laser Power Control circuit.
- Built in RF amplifier.
- Built in focus error amp and tracking error amp.
- Built in sub-beam adder signal amplifier.
- Capable of tracking balance control with TC9432AF/TC9462F.
- Capable of RF gain adjustment circuit with TC9432AF/TC9462F.
- Built in signal amplifier for track counter.
- Capable of 4 times speed operation.
- 24 pin mini flat package.



Weight: 0.3 g (typ.)

Block Diagram



SEL	LDC		
	SW1	SW2	SW3
L	ON	OFF	OFF
HiZ	OFF	ON	ON
H	OFF	ON	ON

Pin Function

Pin No.	Symbol	I/O	Functional Description	Remark
1	V _{CC}	—	Power supply input terminal	—
2	FNI	I	Main beam I-V amp input terminal	Connected to pin diode A, C
3	FPI	I	Main beam I-V amp input terminal	Connected to pin diode B, D
4	TPI	I	Sub beam I-V amp input terminal	Connected to pin diode F
5	TNI	I	Sub beam I-V amp input terminal	Connected to pin diode E
6	MDI	I	Monitor photo diode amp input terminal	Connected to monitor photo diode
7	LDO	O	Laser diode amp output terminal	Connected to laser control circuit
8	SEL	I	Laser diode control signal input terminal and APC circuit ON/OFF control signal input terminal	3 signal input (V _{CC} , HiZ, GND)
9	TEB	I	Tracking error balance adjustment signal input terminal Controlled by 3 PWM signal (PWM carrier = 88.2 kHz)	3 signal input (2 V _{REF} , VR, GND)
10	2VRO	O	Reference voltage (2 V _{REF}) output terminal 2 V _{REF} = 4.2 V when V _{CC} = 5 V	—
11	TEN	I	TE amp negative input terminal	Connected to TEO through feedback register
12	TEO	O	TE error signal output terminal	—
13	SBAD	O	Sub beam adder signal output terminal	—
14	FEO	O	Focus error signal output terminal	—
15	FEN	I	FE amp negative input terminal	Connected to FEO through feedback register
16	VRO	O	Reference voltage (V _{REF}) output terminal V _{REF} = 2.1 V when V _{CC} = 5 V	—
17	RFRP	O	Track count signal output terminal	—
18	RFIS	I	RFRP detect circuit input terminal	Connected to RFO through condenser
19	RFGO	O	RF gain signal output terminal	—
20	RFGC	I	RF amplitude adjustment control signal input terminal Controlled by 3 PWM signal (PWM carrier = 88.2 kHz)	3 signal input (2 V _{REF} , VR, GND)
21	AGCI	I	RF signal amplitude adjustment amp input terminal	Connected to RFO through condenser
22	RFO	O	RF signal output terminal	—
23	GND	—	Ground terminal	—
24	RFN	I	RF amp negative input terminal	—

Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Power supply voltage	V _{CC}	8	V
Power dissipation	P _D	400	mW
Operating temperature	T _{opr}	−40~85	°C
Storage temperature	T _{stg}	−55~150	°C

Electrical Characteristics (unless otherwise specified, $V_{CC} = 5\text{ V}$, $T_a = 25^\circ\text{C}$)

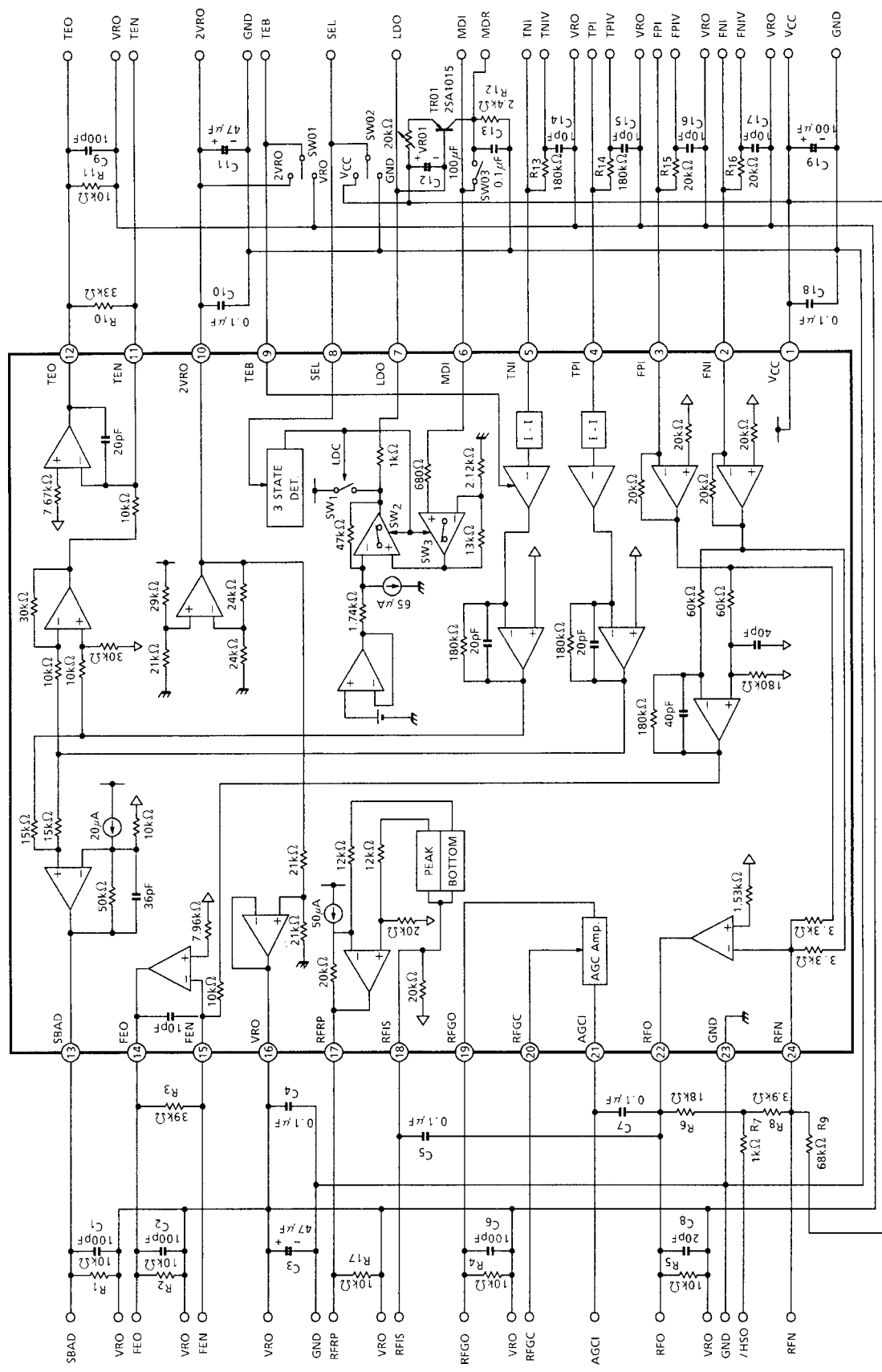
AC Characteristics

Characteristics		Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Power supply	Assured supply voltage	V_{CC}	1	—	4.5	5.0	5.5	V
	Power supply voltage	I_{CC}	1	$SEL = V_{CC}$	18	24	30	mA
Reference voltage: $2V_{REF}$	Reference voltage	$2V_R$	1	—	4.0	4.2	4.4	V
	Output current	I_{OH2}	1	$\Delta V = -0.1\text{ V}$	3.0	—	—	mA
	Input current	I_{OL2}	1	$\Delta V = +0.1\text{ V}$	0.1	—	—	mA
Reference voltage: V_{REF}	Reference voltage	V_R	1	—	2.0	2.1	2.2	V
	Reference voltage limit	ΔV_R	1	$2 \times V_R/2\text{ V} - 1$	-3.0	0.0	+3.0	%
	Output current	I_{OH1}	1	$\Delta V = -0.1\text{ V}$	5.0	—	—	mA
	Input current	I_{OL1}	1	$\Delta V = +0.1\text{ V}$	5.0	—	—	mA
RF1 FPI (FNI) → RFO	Transfer resistance	R_T	1	$f = 100\text{ kHz}$, $R_{NF} = 22\text{ k}\Omega$	117	130	143	$\text{k}\Omega$
	Frequency characteristic	f_c	1	-3dB point	—	5.0	—	MHz
	Output slew rate	SR	1	$C_{RFO} = 20\text{ pF}$	10	20	—	V/ μs
	Noise/Distortion rate	THD	1	$f = 100\text{ kHz}$, $V_{RFO} = 1.2\text{ V}_{p-p}$	—	-40	—	dB
	Upper limit output voltage	V_{OH}	1	GND reference	3.6	—	—	V
	Lower limit output voltage	V_{OL}	1	GND reference	—	—	0.7	V
	Permissive load resistance	R_{LM}	1	—	10	—	—	$\text{k}\Omega$
RF2 (AGC) RFO → RFGO	Lower limit gain voltage	G_{V1}	1	$f = 100\text{ kHz}$, $R_{FGC} = 0.6\text{ V}$	0.66	0.73	0.80	V/V
	Upper limit gain voltage	G_{V2}	1	$f = 100\text{ kHz}$, $R_{FGC} = 3.6\text{ V}$	1.60	1.75	1.90	V/V
	Frequency characteristic	f_c	1	-3dB point	—	5.0	—	MHz
	Output slew rate	SR	1	$C_{RFGO} = 20\text{ pF}$	10	20	—	V/ μs
	Upper limit output voltage	V_{OH}	1	GND reference	3.6	—	—	V
	Lower limit output voltage	V_{OL}	1	GND reference	—	—	0.7	V
	Noise/Distortion rate	THD	1	$f = 100\text{ kHz}$, $V_{RFGO} = 1.2\text{ V}_{p-p}$	—	-40	—	dB
	Permissive load resistance	R_{LM}	1	—	10	—	—	$\text{k}\Omega$
APC MDI → LDO	Gain voltage	G_v	1	$f = 1\text{ kHz}$	—	200	—	V/V
	Operation reference voltage	V_{MDI}	1	$V_{LDO} = 3.5\text{ V}_{DC}$	170	178	192	mV
	LD Off voltage	V_{LDOP}	1	$LDC = L$, V_{CC} reference, $SEL = L$	-0.7	—	—	V
	Input bias current	I_I	1	$V_{MDI} = 178\text{ mV}$	-200	—	+200	nA
FE FNI (FPI) → FEO	Transfer resistance	R_T	1	$f = 1\text{ kHz}$, $R_{NF} = 39\text{ k}\Omega$	198	220	242	$\text{k}\Omega$
	Gain balance	GB	1	—	-1.0	—	+1.0	dB
	Frequency characteristic	f_c	1	-3dB point	—	22	—	kHz
	Output offset voltage	V_{OS}	1	V_R reference, input open	-30	—	+30	mV
	Noise/distortion rate	THD	1	$f = 1\text{ kHz}$, $V_{FEO} = 2.4\text{ V}_{p-p}$	—	-40	—	dB
	Upper limit output voltage	V_{OH}	1	GND reference	3.8	—	—	V
	Lower limit output voltage	V_{OL}	1	GND reference	—	—	0.5	V
	Permissive load resistance	R_{LM}	1	—	10	—	—	$\text{k}\Omega$

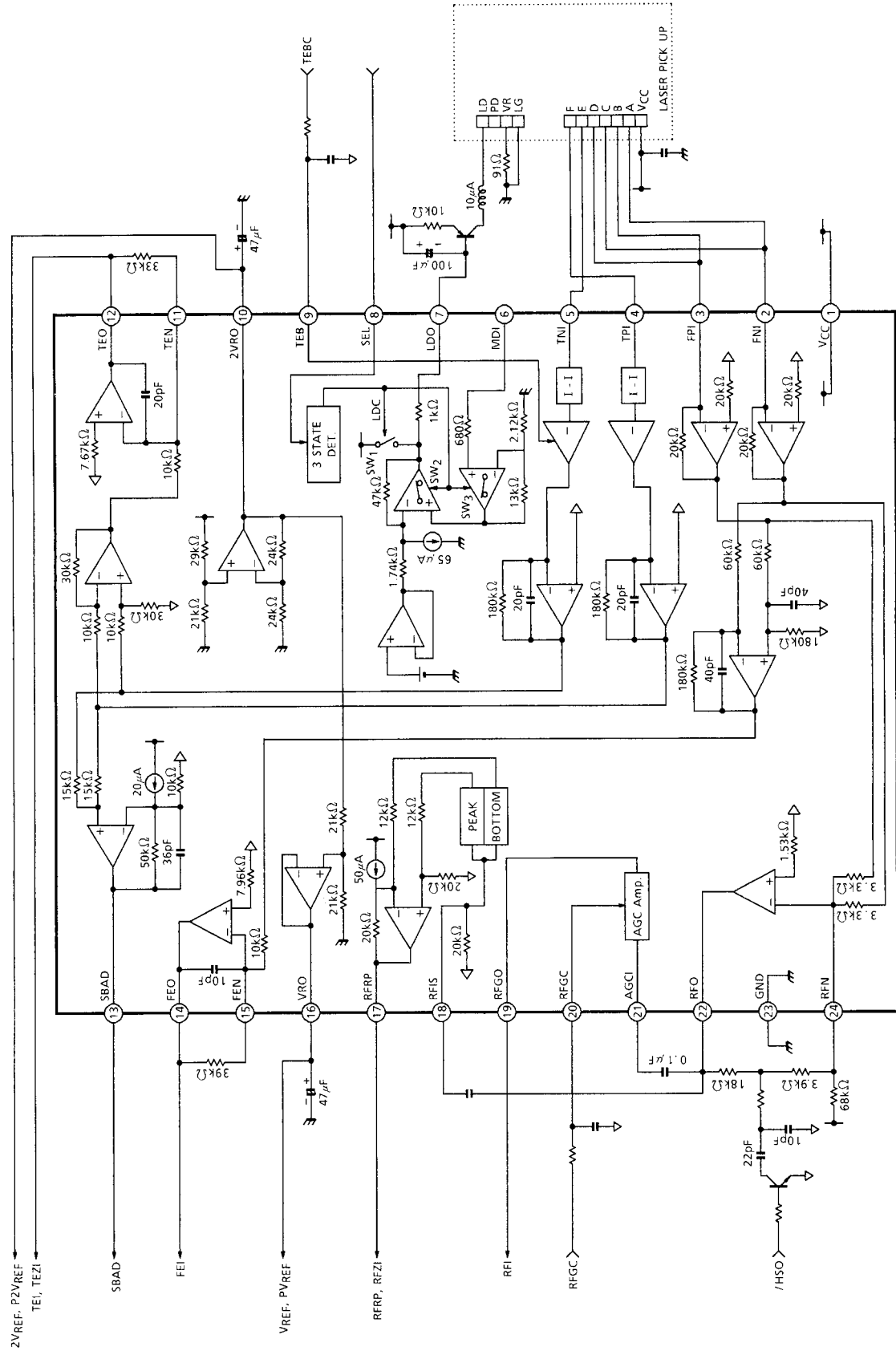
Characteristics		Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
TE TPI (TNI) → TEO	Transfer resistance	R_T	1	$f = 1 \text{ kHz}$, $TEB = VR$, $R_{NF} = 33 \text{ k}\Omega$	1.53	1.70	1.87	$M\Omega$
	Transfer resistance range	ΔR_T	1	TEB = VR reference TEB = GND TEB = 2 VR				
	Max transfer resistance				35	45	55	%
	Min transfer resistance				-55	-45	-35	%
	Gain balance	GB	1	TEB = VR	-1.0	—	+1.0	dB
	Frequency characteristic		1	$R_{NF} = 33 \text{ k}\Omega$				
	Cut-Off frequency 1	f_{c1}			—	44	—	kHz
	Cut-Off frequency 2	f_{c2}			—	240	—	kHz
	Output offset voltage	V_{OS}	1	VR reference, input open	-80	—	+80	mV
	Noise/Distortion rate	THD	1	$f = 1 \text{ kHz}$, $V_{TEO} = 2.0 V_{p-p}$	—	-40	—	dB
	Upper limit output voltage	V_{OH}	1	GND reference	3.8	—	—	V
SBAD TPI (TNI) → SBAD	Lower limit output voltage	V_{OL}	1	GND reference	—	—	0.5	V
	Permissive load resistance	R_{LM}	1	—	10	—	—	$k\Omega$
	Transfer resistance	R_T	1	$f = 1 \text{ kHz}$, $TEB = VR$	416	520	624	$k\Omega$
	Frequency characteristic	f_c	1	-3dB point	—	44	—	kHz
	Noise/Distortion rate	THD	1	$f = 1 \text{ kHz}$, $V_{SBAD} = 1.5 V_{p-p}$	—	-40	—	dB
	Operation reference voltage	V_{OPR}	1	TNI/TPI = VR, VR reference	-1.1	-1.0	-0.9	V
				TNI/TPI = HiZ, VR reference	-1.2	-1.1	-1.0	
RFRP RFIS → RFRP	Upper limit output voltage	V_{OH}	1	GND reference	3.8	—	—	V
	Permissive load resistance	R_{LM}	1	—	10	—	—	$k\Omega$
	Gain voltage	G_v	1	—	1.37	1.46	1.54	V/V
	Detection frequency characteristic	f_c	—	$SEL = V_{CC}$	—	100	—	kHz
	Operation reference voltage 1	V_{OPR1}	1	VR reference, No signal	-1.1	-1.0	-0.9	V
	Operation reference voltage 2	V_{OPR2}	1	VR reference, 700 kHz, $1.2 V_{p-p}$	+0.65	+0.75	+0.85	V
	Permissive load resistance	R_{LM}	1	—	10	—	—	$k\Omega$

Note: If the IC is used abnormally (ex. wrongly mounted), it may be damaged or destroyed.

Test Circuit



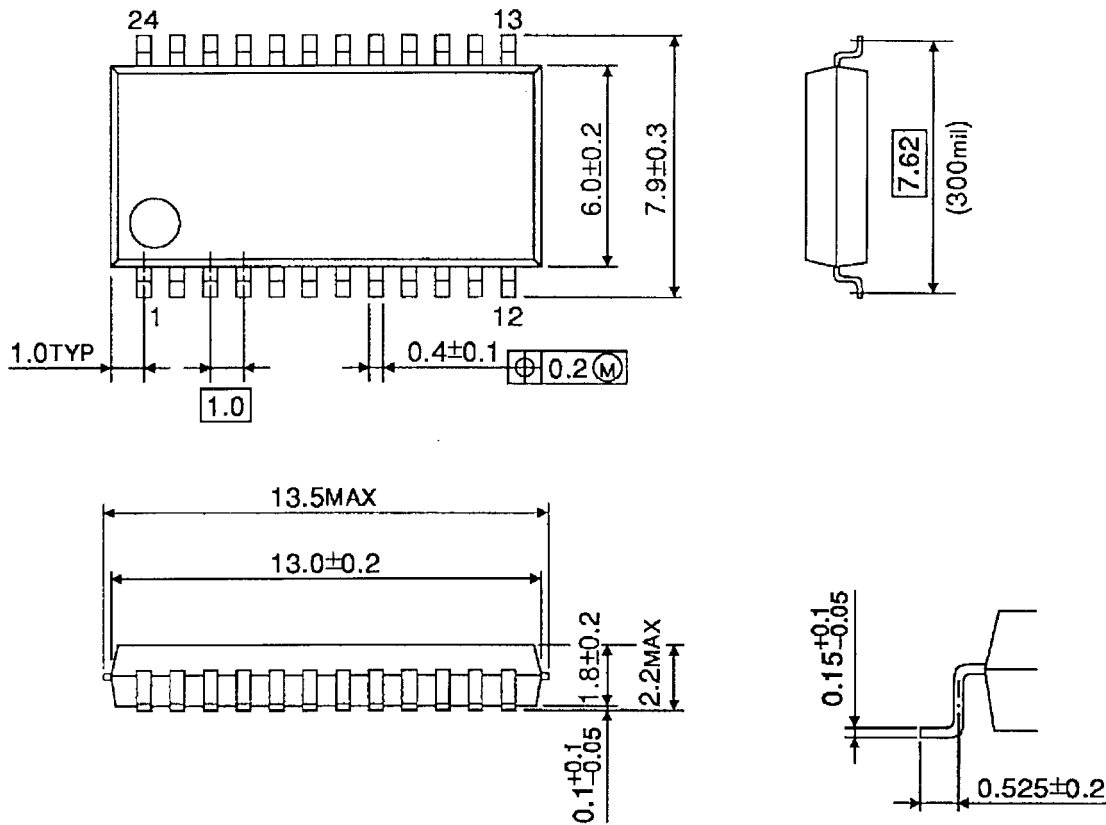
Application Circuit



Package Dimensions

SSOP24-P-300-1.00

Unit : mm



Weight: 0.3 g (typ.)

RESTRICTIONS ON PRODUCT USE

000707EBA

- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- The products described in this document are subject to the foreign exchange and foreign trade laws.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others.
- The information contained herein is subject to change without notice.